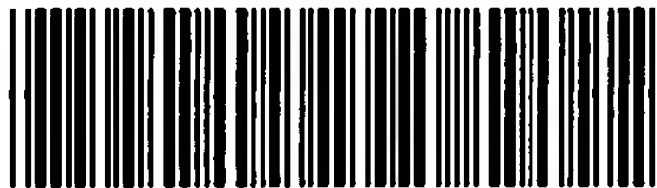


**Search Notes (continued)**

Application/Control No.

10/618,302

Examiner

Syed Zaidi

Applicant(s)/Patent under  
Reexamination

HONKEN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
375	260	5/29/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	5/29/2007	SZ
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